A Workshop on

Measurement Methods for Evaluation of the Reliability of Active Implantable Medical Devices

October 3–4, 2005

Lecture Room B
Administration Building, Building 101
National Institute of Standards and Technology
Gaithersburg, MD 20899

Conference Chairperson

William F. Regnault U.S. Food and Drug Administration

Conference Co-chairperson

Elizabeth S. Drexler
Materials Reliability Division
National Institute of Standards and Technology

Conference Co-chairperson

John A. Tesk Biomedical Materials and Devices Consulting

Sponsored by:

US Food and Drug Administration (FDA) http://www.fda.gov/
Center for Devices and Radiological Health http://www.fda.gov/cdrh/
National Institute of Standards and Technology (NIST) http://www.nist.gov/
Materials Science & Engineering Laboratory http://www.msel.nist.gov/
Materials Reliability Division http://www.msel.nist.gov/
Polymers Division http://www.msel.nist.gov/
Manufacturing Engineering Laboratory http://www.mel.nist.gov/

With cooperation of: The American Society for Testing and Materials International (ASTM) http://www.astm.org/

Pre-registration is required, on-site registration is not available.

To pre-register go to: https://rproxy.nist.gov/CRS/conf ext.cfm?conf id=1485

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Measurement Methods for Evaluation of the Reliability of **Active Implantable Medical Devices**

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Agenda

October 3,	Day 1			
8:00 AM	Registration & Continental Breakfast			
8:55 AM	Introductions, Moderator, John A. Tesk			
9:00 AM	Welcome to the Workshop, NIST & the FDA	Rich Kayser NIST		
9:10 AM	NIST & Biomaterials	Lori Henderson NIST		
9:20 AM	Introduction to the Workshop Issues	William F. Regnault FDA		
Plenary Sessions I, II & III Moderator, William F. Regnault, FDA				
09:35 AM	Plenary Session I			
09:35 AM	Patient Perceptions leading to Explantation	James Kane FDA		
10:00 AM	Post-Market Regulation of Medical Devices	Betty Collins FDA		
10:25 AM	GMP Regulations and Standards	Jan Welch FDA		
10:45 AM	BREAK			
11:00 AM	Plenary Session II – Designing for Intended Use and Re	eliability Ali Mosleh U MD		
11:30 AM	Plenary Session III – MIL-STDS and Consensus Standards – Their Utility and their Inference for Device Reliability			
11:30 AM	What Standards are Needed?	Celeste Null Intel		
12:00 AM	Issues Surrounding the Use of Standards and Test Methods	Open Discussion		
12:30 PM	Lunch, NIST Cafeteria			
	Working Sessions I & II Moderator, Elizabeth Dre			
01:30 PM				
	Session Chair: Jack Martinez	NIST		
01:30 PM	Chip-level Design: Developments, Failure Mechanisms and			
01.301141	emp level Besign. Bevelopments, I unare ivicentumisms une	Ken Rodbell IBM		
01:50 PM	Package-level Design: Developments, Failure Mechanisms and Reliability Testing			
		Robert Munroe (Retired) Motorola		
02:10 PM	Residual Gas Content and Ionic Content	Bob Thomas (Retired) Rome AFB		
02:30 PM	Answers for Advice that the Workshop Seeks (see Session Chair's Guide)			
03:30 PM	BREAK			
03:45 PM	Working Session II – Plausible Mechanisms for Failure: Mechanisms Outside the Can			
	Session Chair: Michael Schen	NIST		
03:45 PM		Robert Baboian RB Corrosion Service		
04:05 PM	Impact, Trauma, and Vibration Issues	Dominick Hammerer Med-El		
04:25 PM	Answers for Advice that the Workshop Seeks (see Session Chair's Guide)			
05:25 PM	End of Day 1			

OCTOBER 4, DAY 2

7:45 AM	Registration & Continental Breakfast		
8:45 AM	Working Session III		
	Measurements for Accelerated Reliability Testi	ing of Packages	
	Session Chair: Stan Purwin	Johns Hopkins University	
Applied Phy	ysics Laboratory		
08:45AM	What are the Proper Accelerators for Predicting the Reliab	pility of Active Implantable Medical	
	Devices?	Michael G. Pecht U MD	
09:05 AM	Answers for Advice that the Workshop Seeks (see Session Chair's Guide)		
10:05 AM	BREAK		
10:20 AM	Working Session IV, Medical System Concerns- Manufacturers' Perspectives		
	Session Chair: Keith McLain	Advanced Bionics Inc.	
10:20 AM		David Erhart Medtronic	
10:40 AM	E	dmond Capcelea Cochlear Corporation	
11:00 AM	Answers for Advice that the Workshop Seeks (see Session Chair's Guide)		
12:00 PM	Lunch, NIST Cafeteria		
01:00 PM	Session Chairs to Draft Workshop Summary		
01:00 PM	Working Session V, Reliability Issues for Futu	ure Devices	
	Session Chair: John Suehle	NIST	
(This sossio	on is onen to all except the previous session chairs and pr	econtare from their eassions who wish	

to work with their session chairs on developing Summary Recommendations) 02:15 PM Conclusion and Summary Recommendations

Who is to do what? Where is the work to be done? How is the work to be accomplished?

Is there a need for a follow-up workshop or symposium?

3:00 PM: **End of Workshop**

Planning Committee

William F. Regnault, Center for Devices and Radiological Health, FDA Elizabeth S. Drexler, Materials Reliability Division, NIST John A. Tesk, Consultant Michael Schen, Advanced Technology Program, NIST